



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	

# Thermal characteristics<sup>2)</sup>

Thermal resistance, junction - case	$R_{\mathrm{thJC}}$	-	-	-	1.7	K/W
SMD version, device on PCB	$R_{\mathrm{thJA}}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>3)</sup>	-	-	40	

**Electrical characteristics,** at  $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, <i>I</i> <sub>D</sub> = -1mA	-40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -150 \mu \text{A}$	-2.0	-3.0	-4.0	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =-32V, V <sub>GS</sub> =0V, 7 <sub>j</sub> =25°C	-	-0.05	-1	μΑ
		$V_{DS}$ =-32V, $V_{GS}$ =0V, $T_{j}$ =125°C <sup>2)</sup>	-	-20	-200	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	-	-	-100	nA
Drain-source on-state resistance	$R_{\rm DS(on)}$	V <sub>GS</sub> =-10V, / <sub>D</sub> =-85A	-	5.3	7.3	mΩ





Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics <sup>1)</sup>						
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V, f=1MHz	-	4681	6085	pF
Output capacitance	C <sub>oss</sub>		-	1520	2280	
Reverse transfer capacitance	C <sub>rss</sub>		-	45	91	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =-20V, V <sub>GS</sub> =-10V, / <sub>D</sub> =-85A, R <sub>G</sub> =3.5Ω	-	24	-	ns
Rise time	t <sub>r</sub>		-	15	-	
Turn-off delay time	t <sub>d(off)</sub>		-	34	-	
Fall time	t <sub>f</sub>		-	39	-	
Gate Charge Characteristics <sup>1)</sup>		ſ	1	r		
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =-32V, / <sub>D</sub> =-85A, V <sub>GS</sub> =0 to -10V	-	26	34	nC
Gate to drain charge	$Q_{gd}$		-	13	26	
Gate charge total	Qg		-	69	89	
Gate plateau voltage	V <sub>plateau</sub>		-	-5.5	-	V
Reverse Diode						
Diode continous forward current <sup>1)</sup>	I <sub>s</sub>	− <i>T</i> <sub>C</sub> =25°C	-	-	-85	А
Diode pulse current <sup>1)</sup>	I <sub>S,pulse</sub>		-	-	-340	]
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, / <sub>F</sub> =-85A, 7 <sub>j</sub> =25°C	-	-1	-1.3	v
Reverse recovery time <sup>1)</sup>	t <sub>rr</sub>	V <sub>R</sub> =-20V, / <sub>F</sub> =-50A,	-	48	-	ns
Reverse recovery charge <sup>1)</sup>	Q <sub>rr</sub>	d <i>i<sub>F</sub>/dt=</i> -100A/µs	-	54	-	nC

<sup>1)</sup> Defined by design. Not subject to production test.

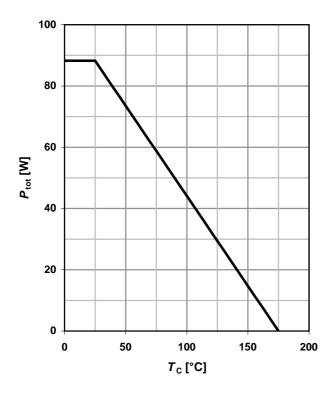
 $^{2)}$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



# 1 Power dissipation

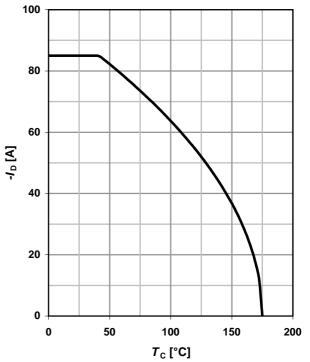
Cinfineon

 $P_{tot} = f(T_C); V_{GS} \le -6V$ 



#### 2 Drain current

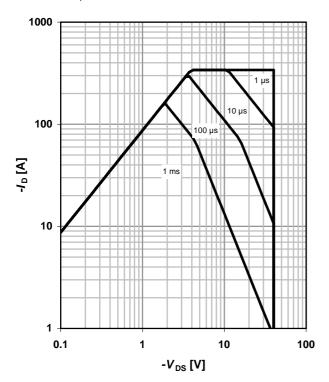
 $I_{\rm D} = f(T_{\rm C}); V_{\rm GS} = -10V$ 



# 3 Safe operating area

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm C} = 25 \text{ °C}; D = 0$ 

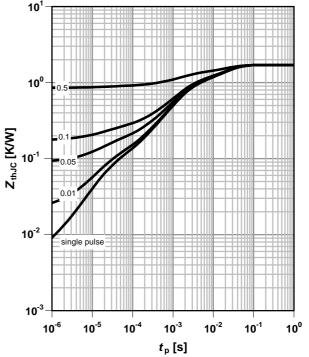
parameter:  $t_p$ 



#### 4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter:  $D = t_p/T$ 



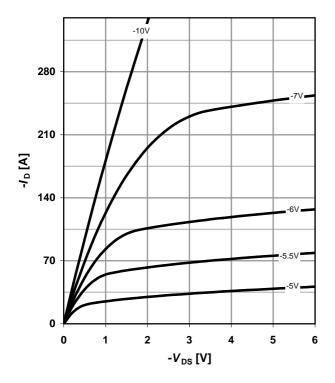
Downloaded from Arrow.com.



#### 5 Typ. output characteristics

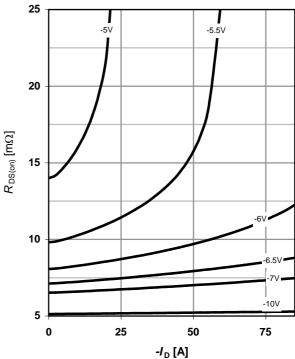
# $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \ ^{\circ}{\rm C}$

parameter: V<sub>GS</sub>



#### 6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}$ parameter:  $V_{GS}$ 

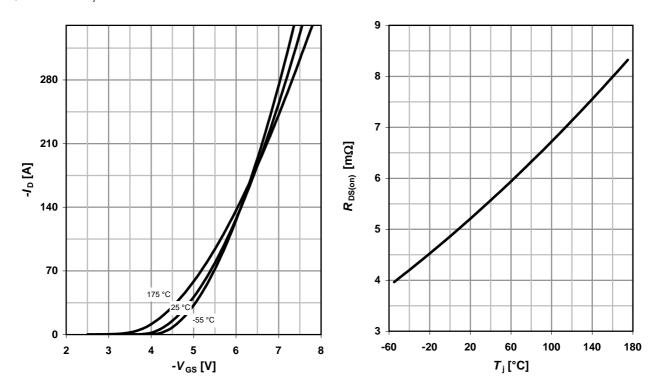


# 7 Typ. transfer characteristics

 $I_{\rm D} = f(V_{\rm GS}); V_{\rm DS} = -6V$ 

8 Typ. drain-source on-state resistance  $R_{DS(on)} = f(T_j); I_D = -85 \text{ A}; V_{GS} = -10 \text{ V}$ 

parameter: T<sub>i</sub>



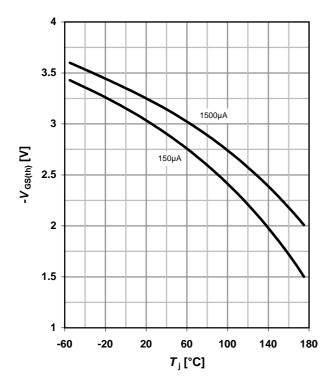




## 9 Typ. gate threshold voltage

# $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: - I D



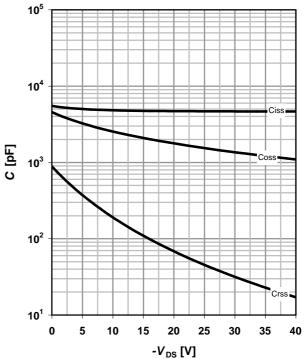
### 11 Typical forward diode characteristicis

 $I_F = f(V_{SD})$ 

parameter: T<sub>i</sub>

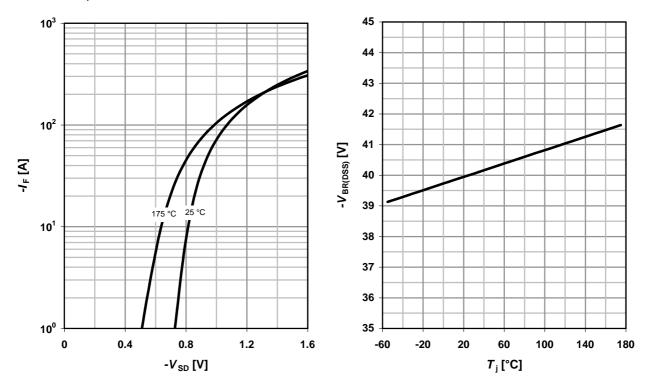


 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 



## 12 Drain-source breakdown voltage

 $V_{BR(DSS)} = f(T_j); I_D = -1 \text{ mA}$ 

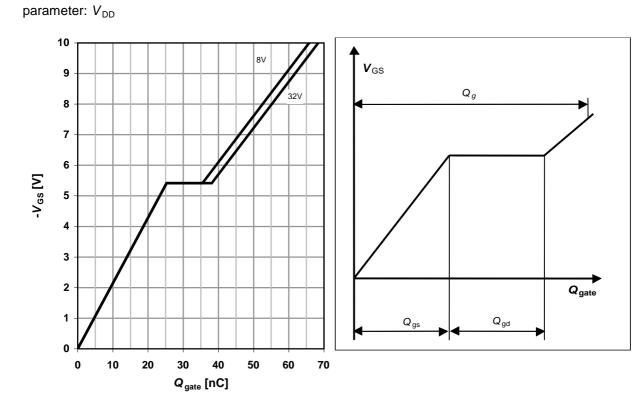




## 13 Typ. gate charge

# 14 Gate charge waveforms

 $V_{GS} = f(Q_{gate}); I_D = -85 \text{ A pulsed}$ 





Published by Infineon Technologies AG 81726 Munich, Germany

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# **Revision History**

Version	Date	Changes
0.1	08.03.2010	Initial Target Data Sheet
0.2	10.12.2010	Preliminary Data Sheet
1.0	15.03.2011	Final Data Sheet